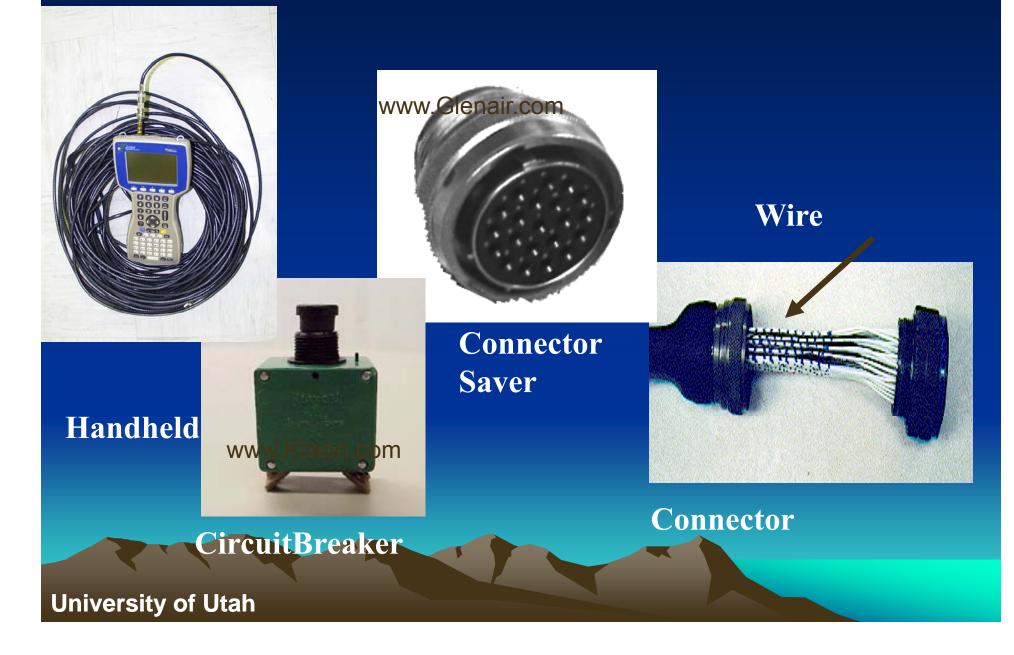
Fault Location on Branched Wire Networks

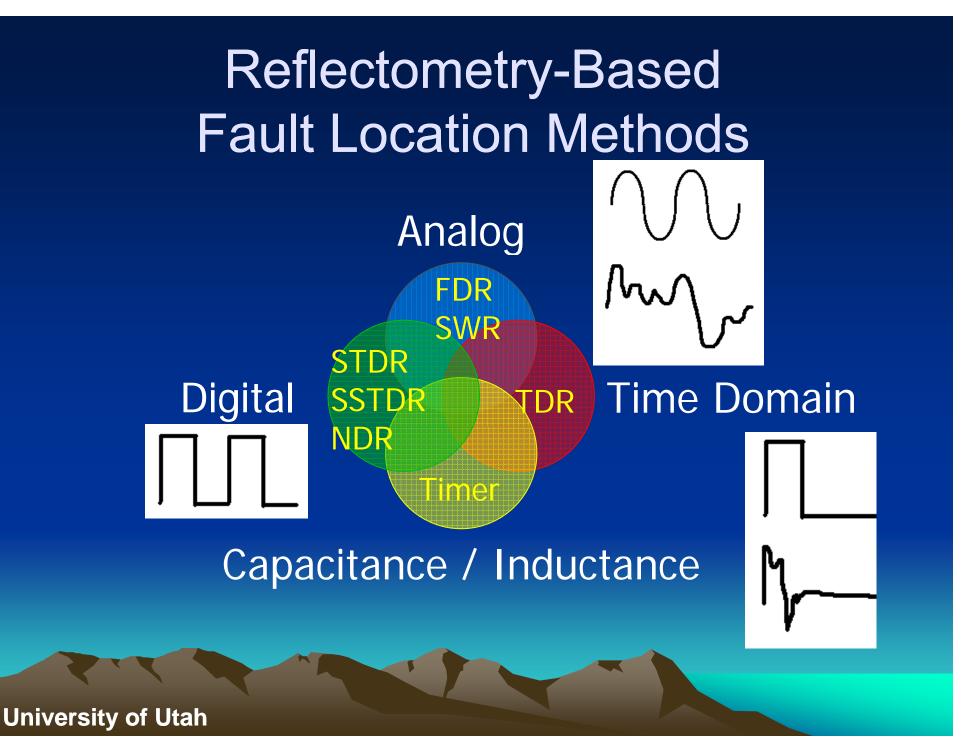
Dr. Chet Lo*, Kedarnath Nagoti*, Dr. You Chung Chung**, Dr. Cynthia Furse*,*** University of Utah*, Center of Excellence for Smart Sensors LiveWire Test Labs, Inc.*** Salt Lake City, Utah Dae Gu University, Korea** Chet Lo, Kedarnath Nagoti, Arthur Mahoney, You Chung Chung[,] Cynthia Furse, "Detection and Mapping of Branched Wiring Networks from Reflectometry Responses," Joint FAA/DoD/NASA Conference on Aging Aircraft, Palm Springs, CA, Jan 31-Feb 4, 2005

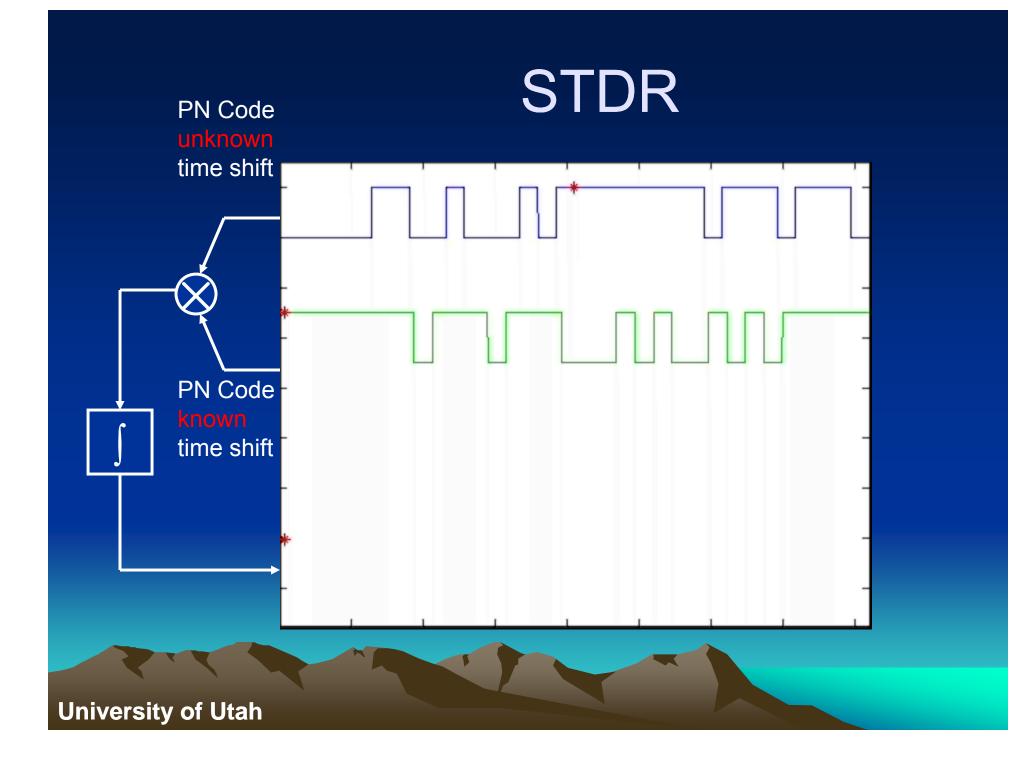
Abstract:

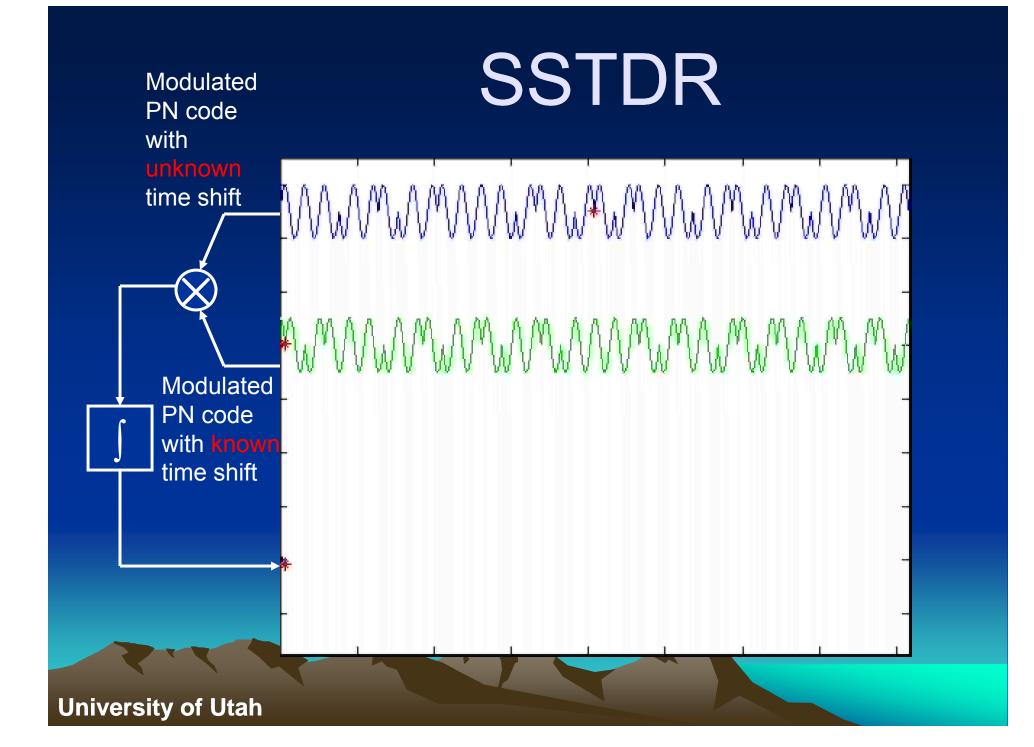
Reflectometry methods including time, frequency, sequence, and spread spectrum reflectometry methods are capable of providing highly accurate location of faults on aircraft wiring. One of the significant challenges in applying these methods in practice is that many wires, particularly power wires, branch into tree-shaped networks from which multiple reflections create extremely difficult-to-interpret reflectometry responses. In this presentation, we will discuss the complexity of the branched network problem and why accurate measurements of the length and magnitude are so critical for solving this problem. We will also introduce two functional novel systematic approaches to solve this problem, which do not require prior measurements as baselines. Additionally, we will present results from our approaches with both simulated and measured reflectometry data of branched networks.Sources of error including measurement error and topology ambiguity are considered, and an assessment of network mapping strategies is given for both ideal and nonideal data

Potential Sensor Locations

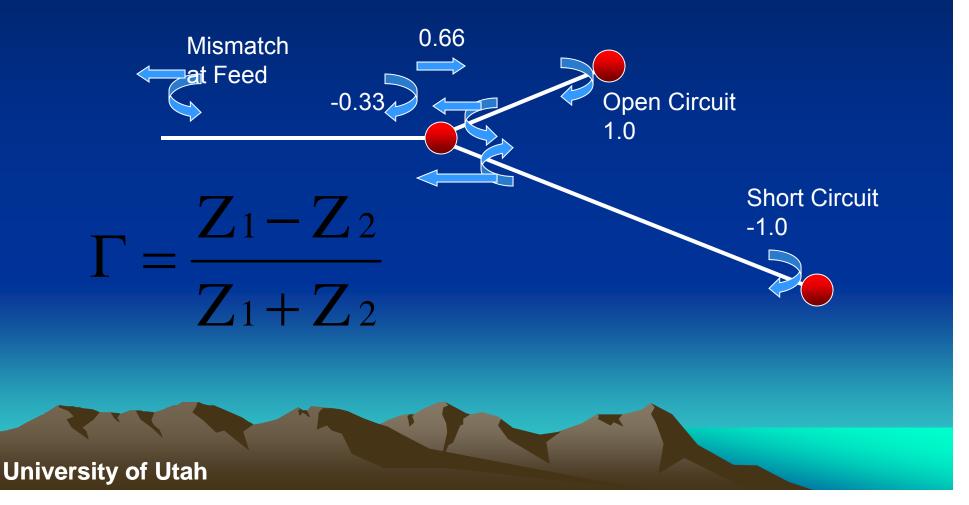






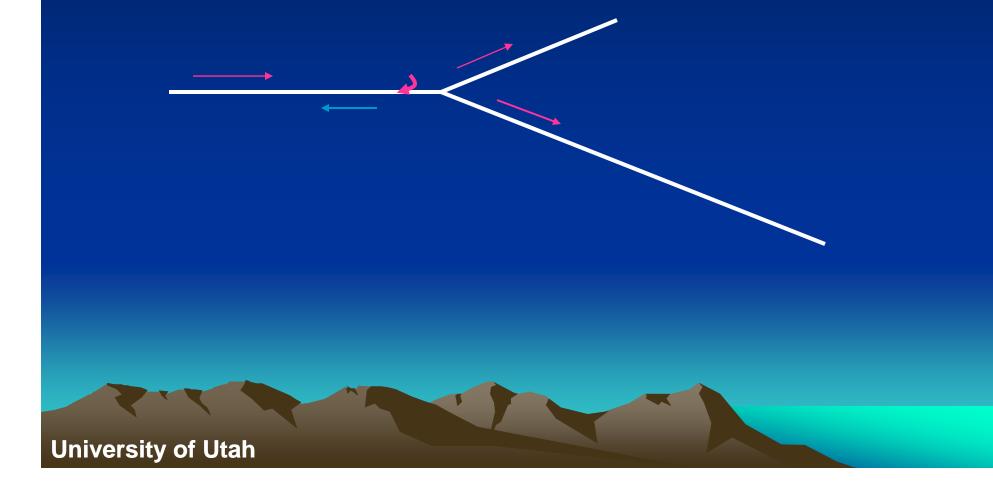


Reflectometry Measures the Reflection at every Impedance CHANGE on the wire

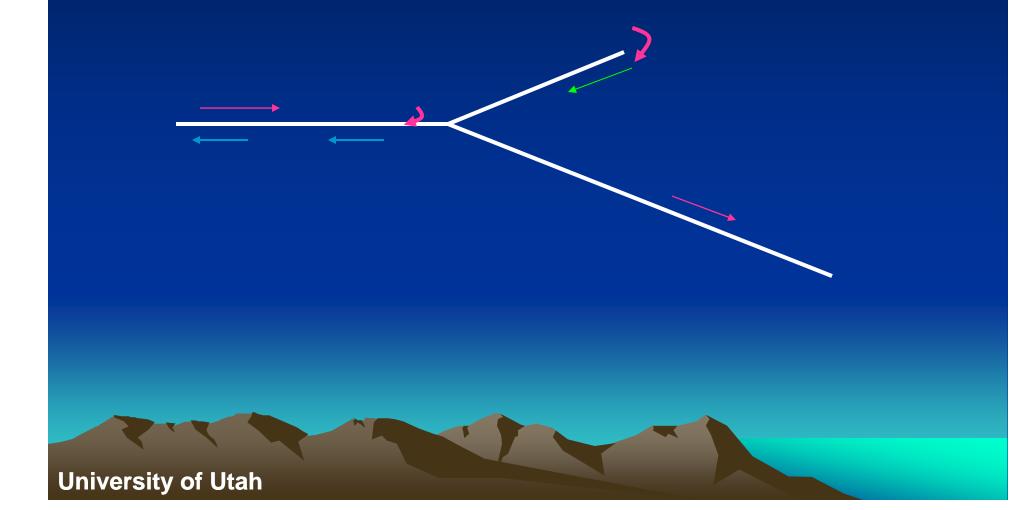




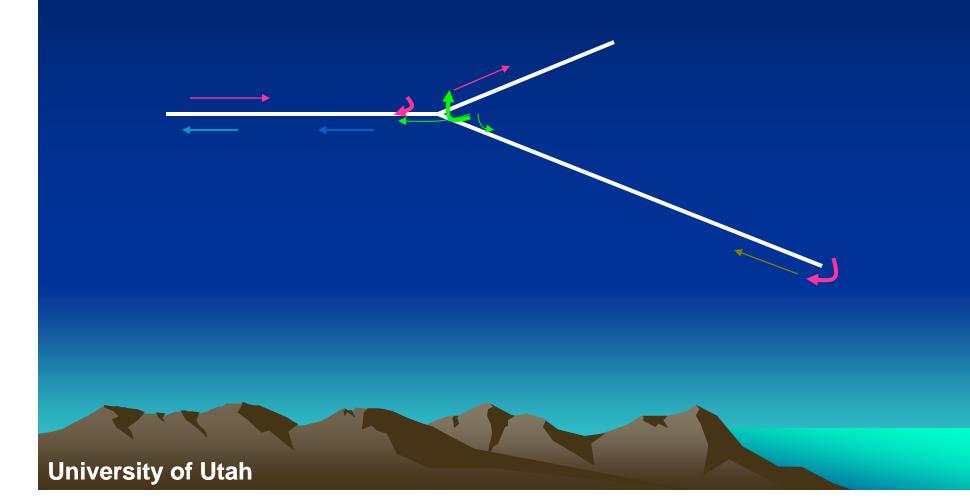


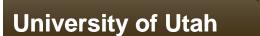


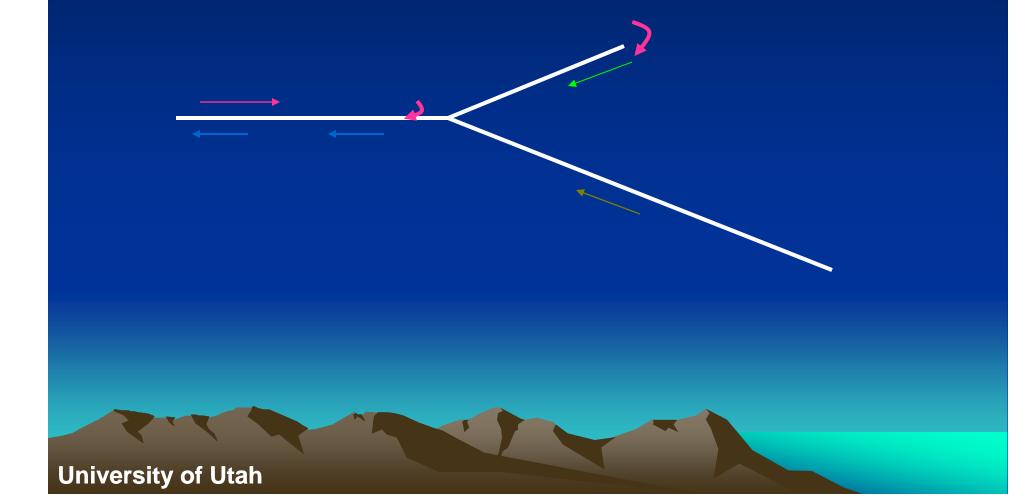




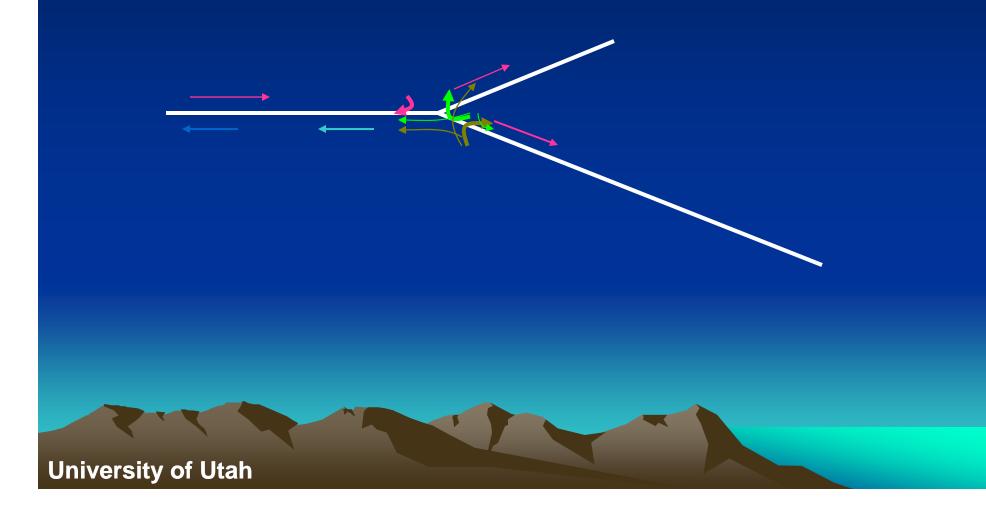


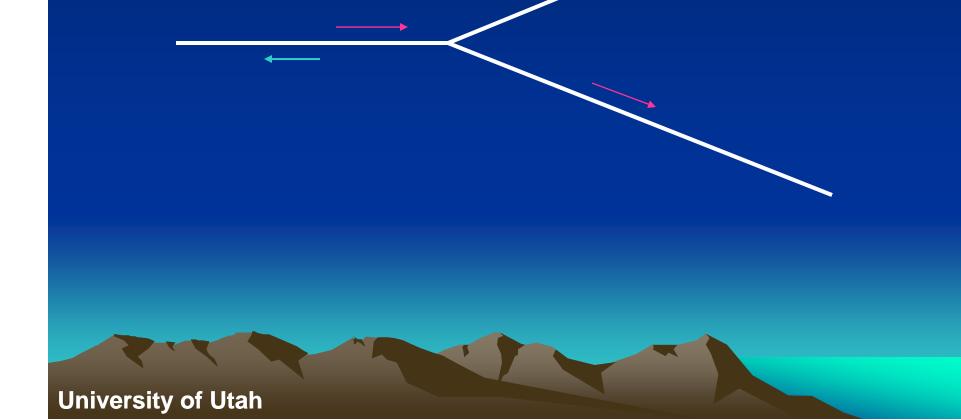


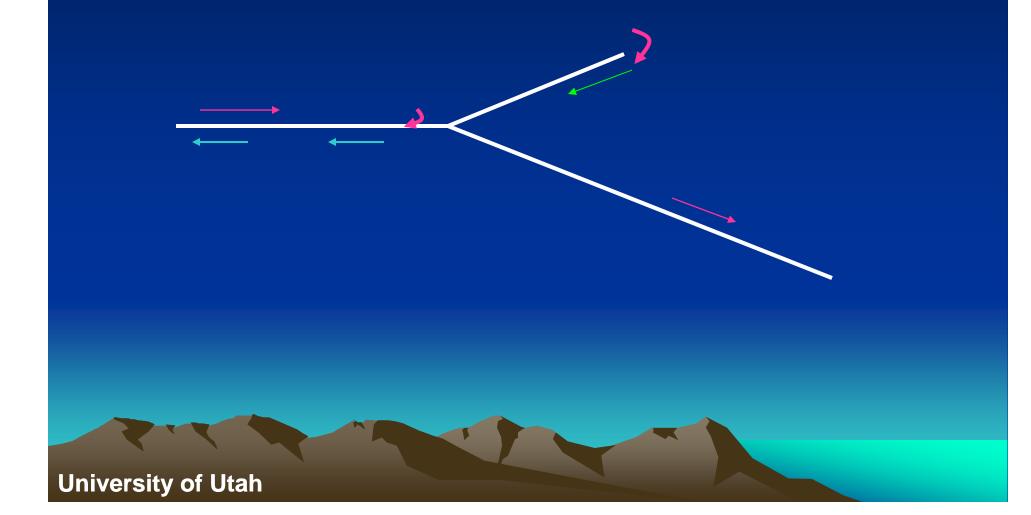




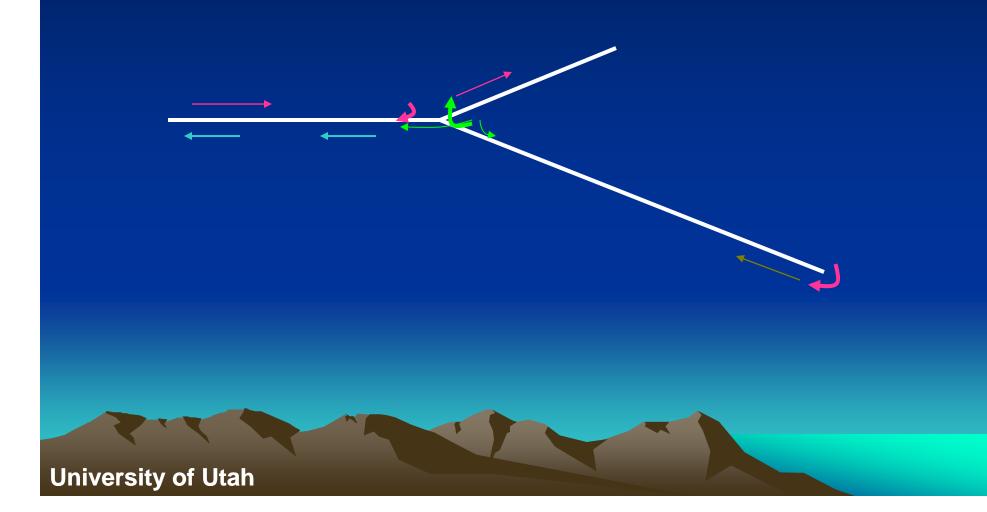


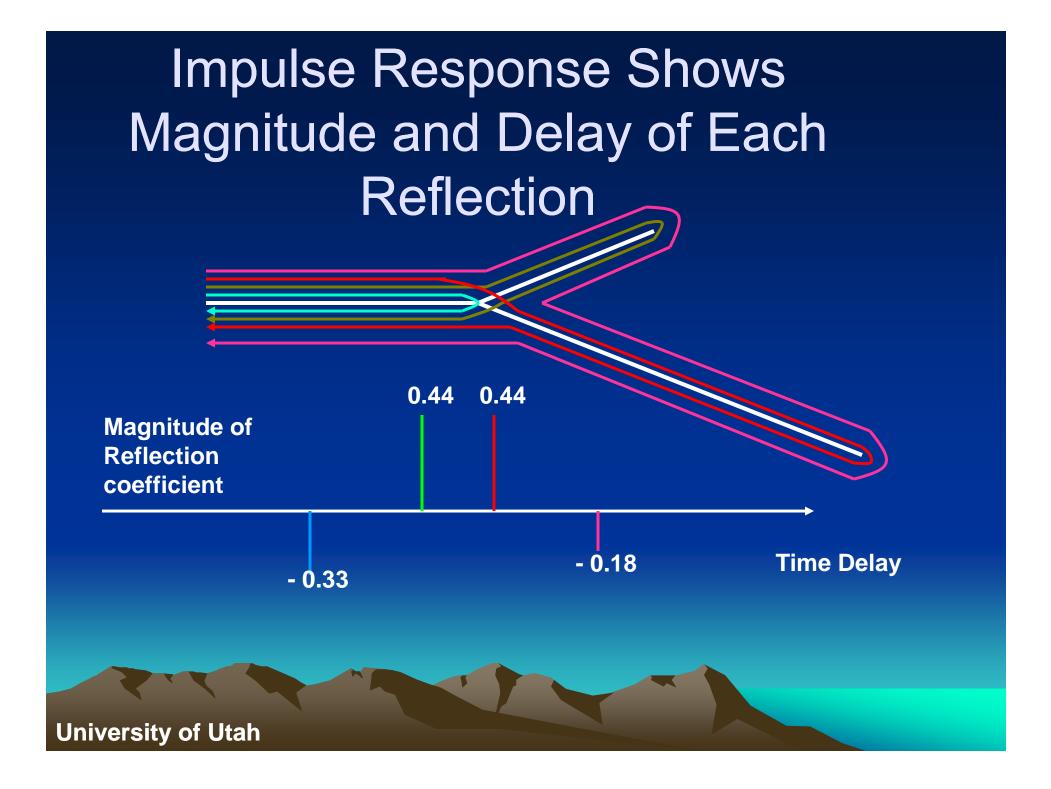




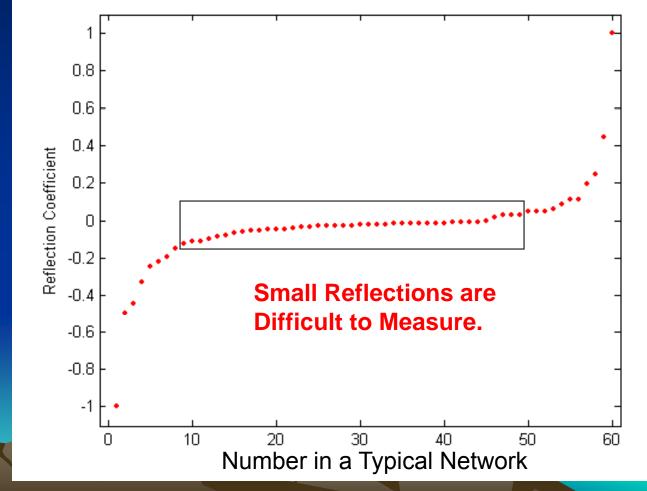




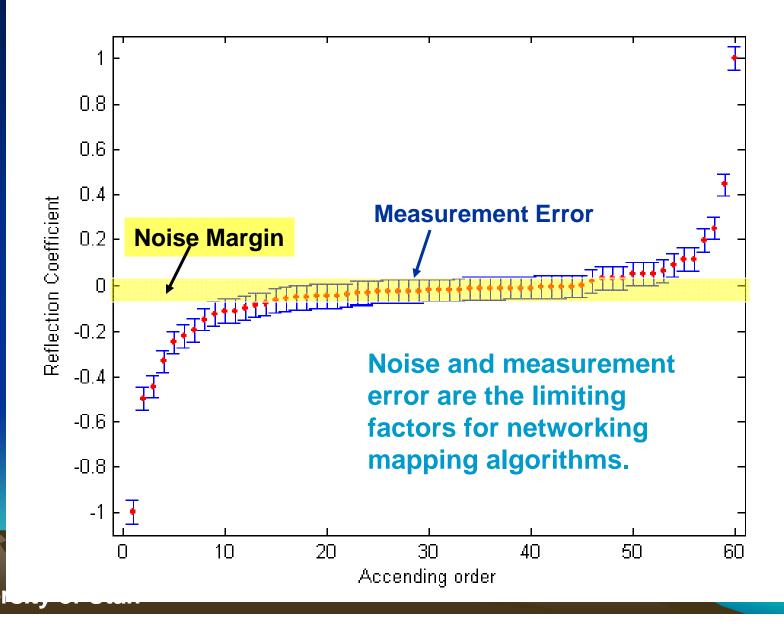




Typical Branched Network Has Many SMALL Reflections

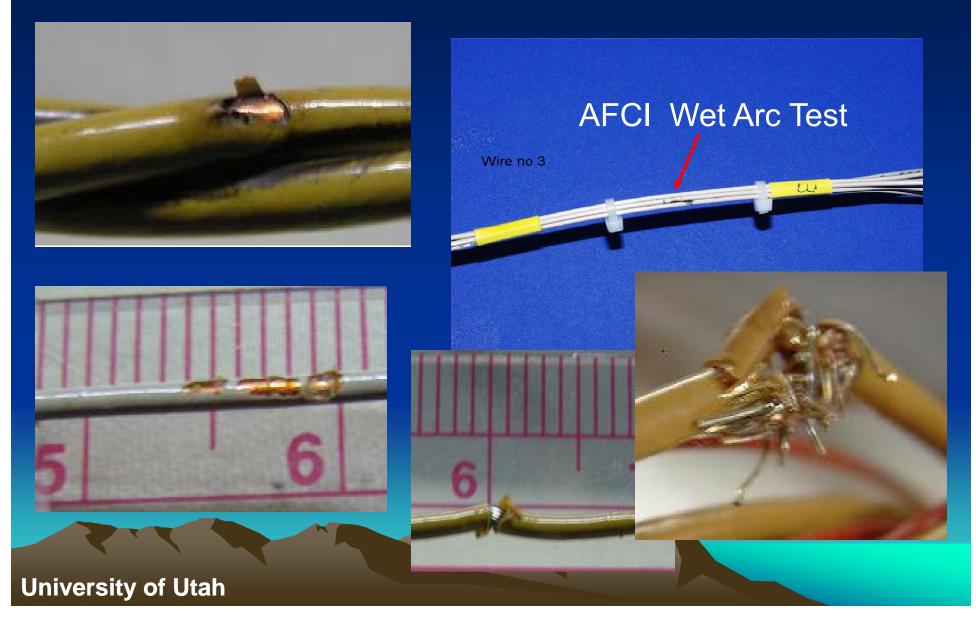


Noise Masks Small Reflections

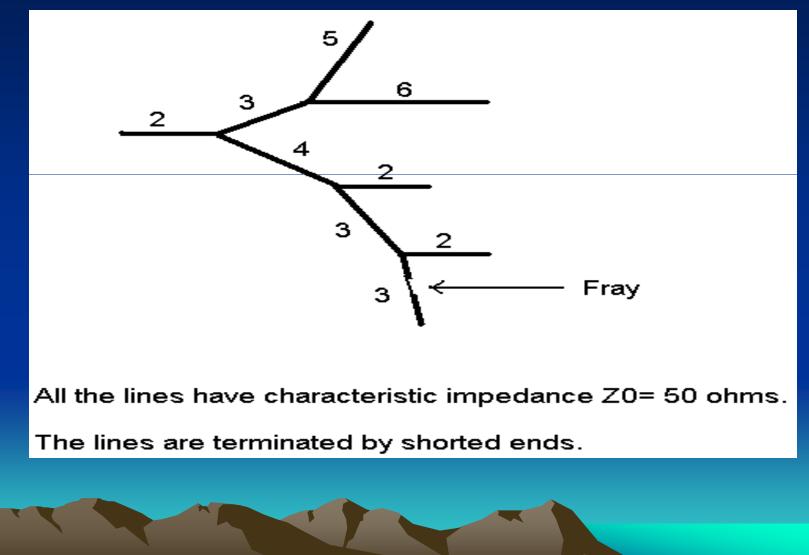


Unive

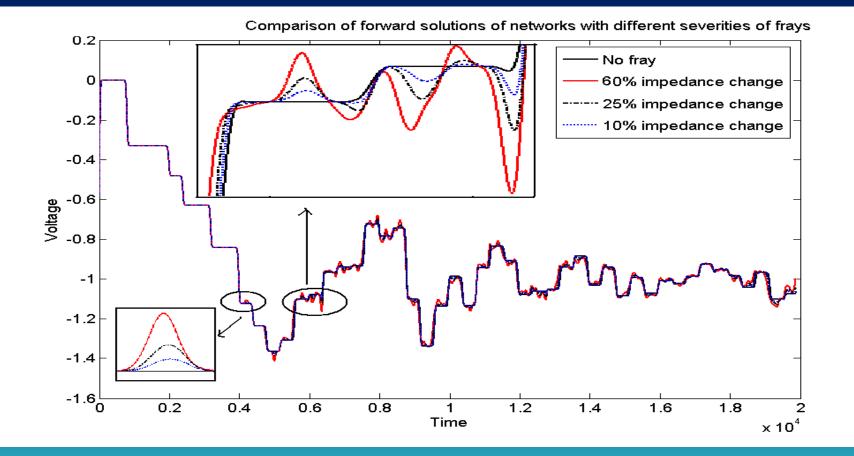
What About FRAYS and ARCS?



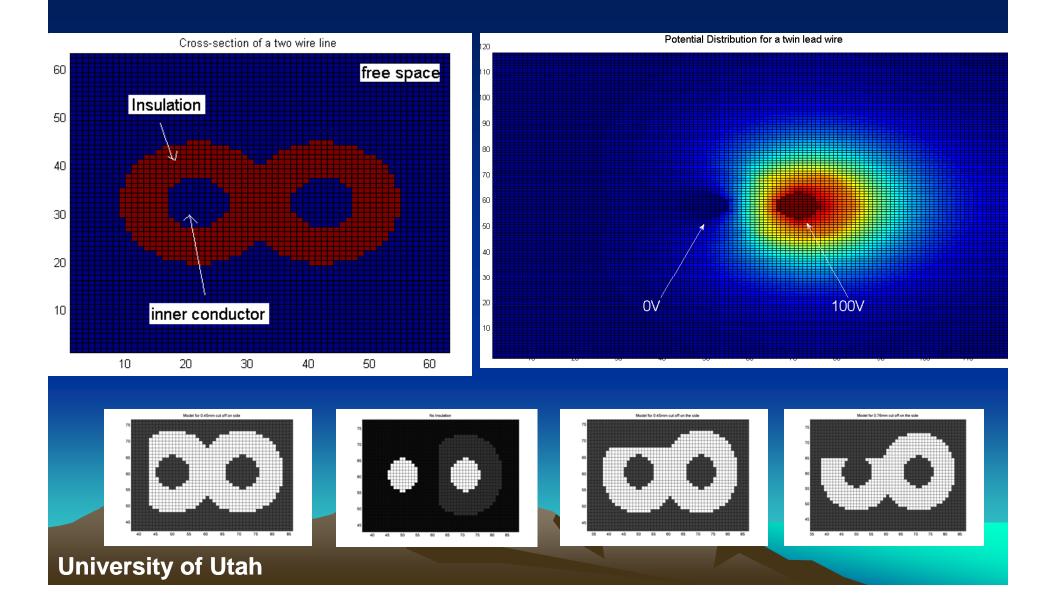
Fray on a Network



Reflectometry Response



Simulated Frays



Fray impedances and reflection coefficients

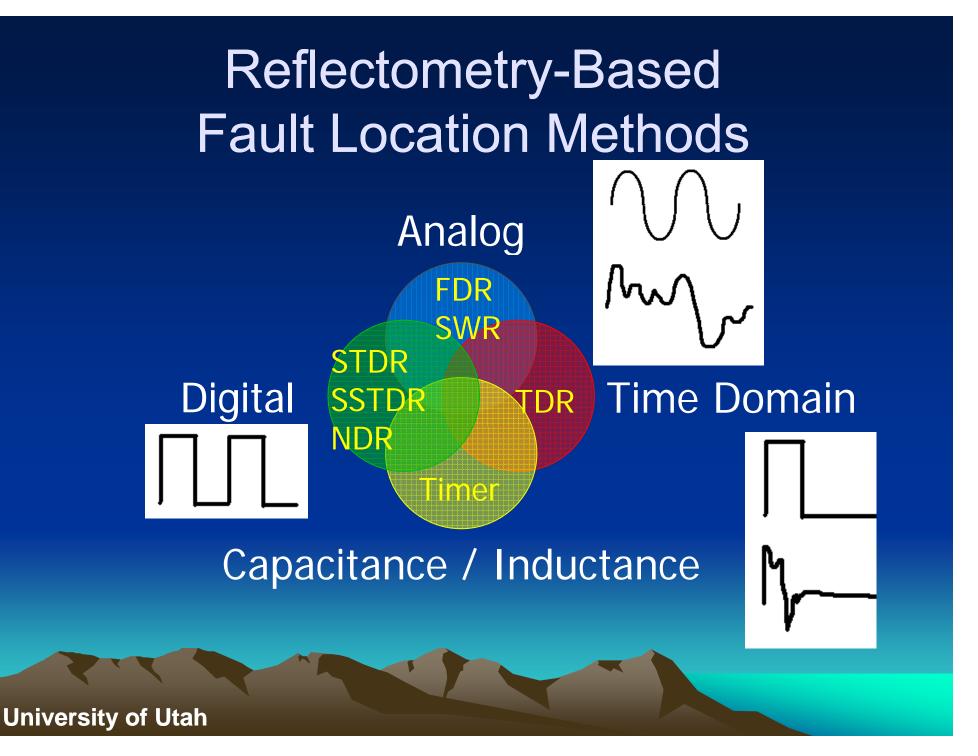
	Scenario	Characteristic Impedance (Ω)	Reflection Coefficient
1	Short Circuit		-100 %
2	Open Circuit		100 %
3	No changes	77.57	0
4	Water Drop	73.81	-2.4 %
5	Cut .15 mm off top	77.59	0.014%
6	Cut .45 mm off top	77.64	0.044%
7	Cut .76 mm off top	78.01	0.28%
8	Cut .15 mm off side	77.57	0.0021%
9	Cut .45 mm off side	77.58	0.0056%
10	Cut .76 mm off side	77.60	0.017%

Fray Impedance is Similar to Normal Impedance Variation on UnControlled Impedance Wire

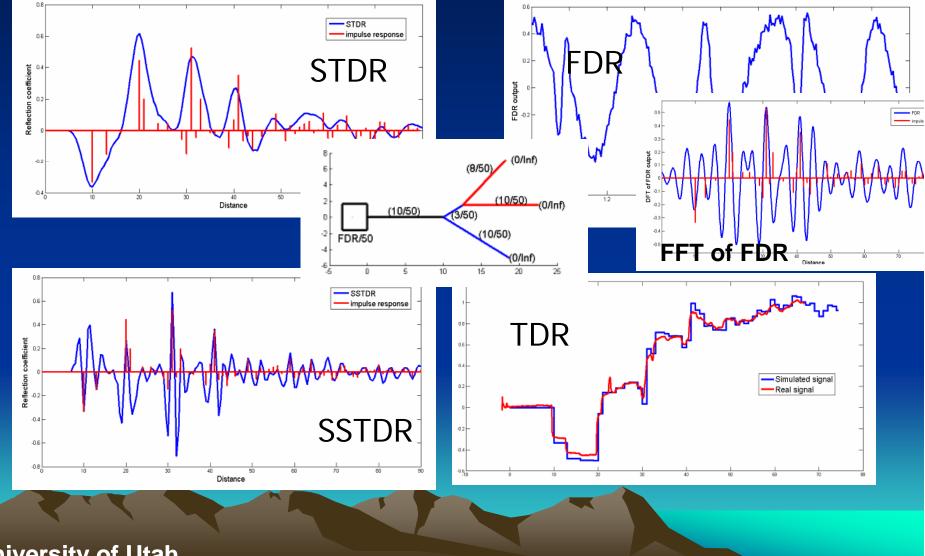


Frays are "Invisible" to Reflectometry

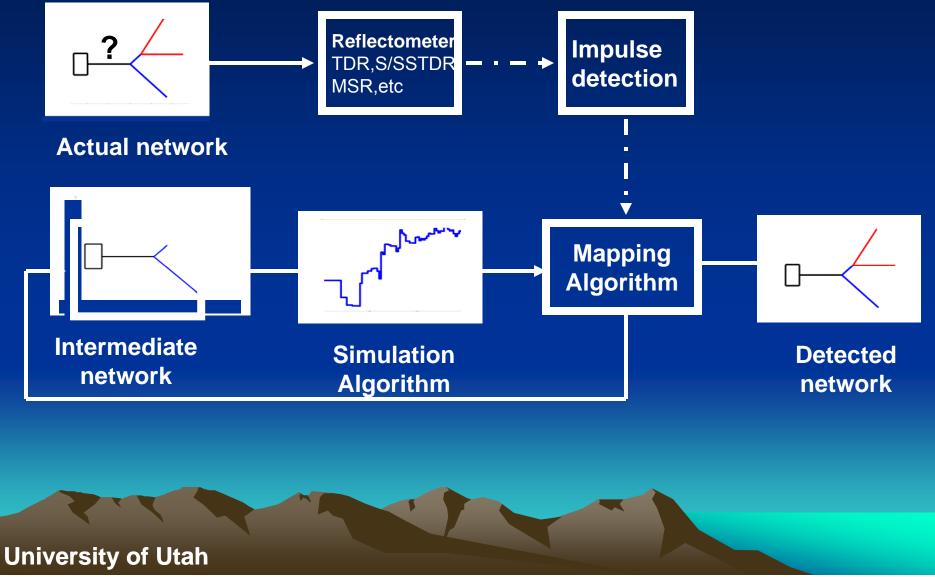
Run "Live" to Locate Intermittent OPEN or SHORT Instead



Reflectometry-Based Fault Location Methods



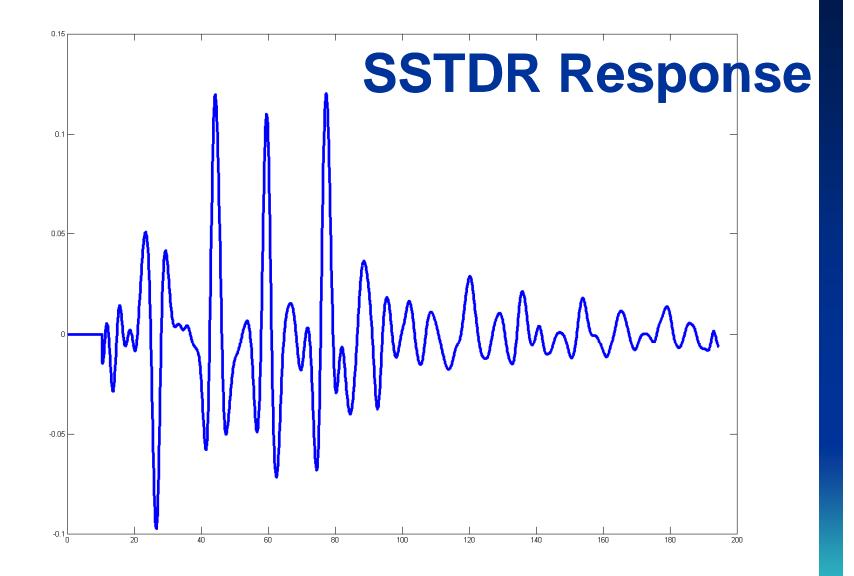
Location of Faults on Branched Network

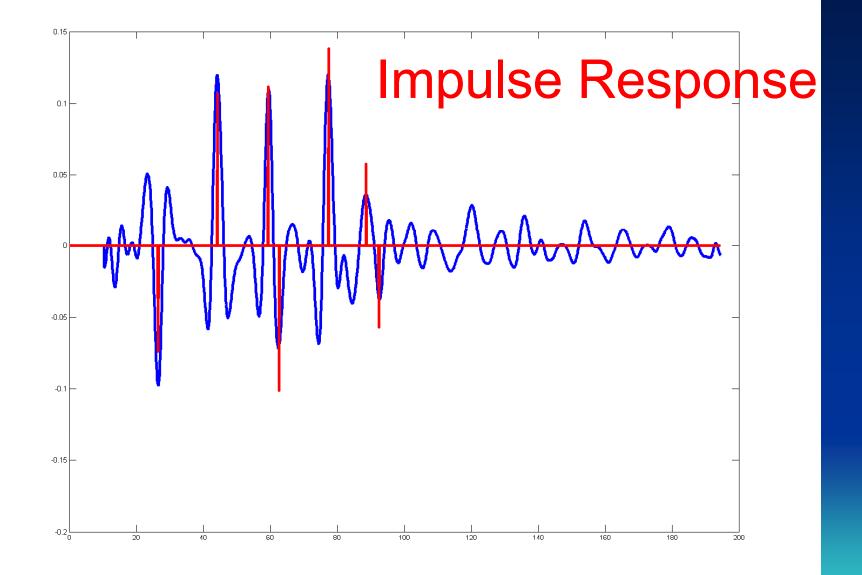


Location of Faults on Branched Network

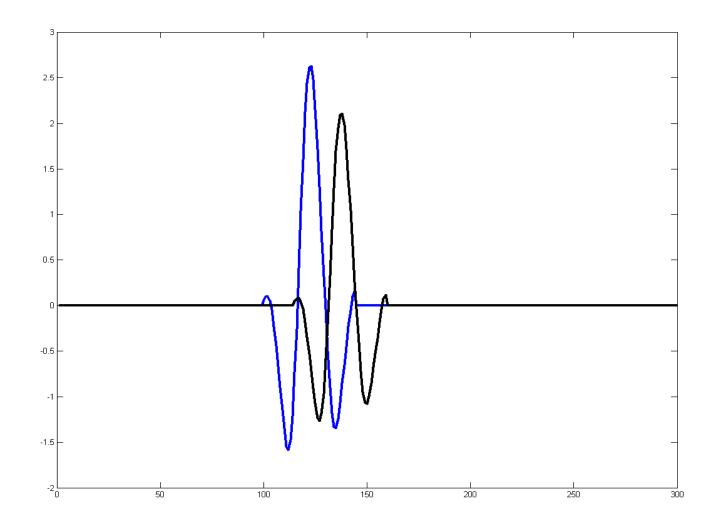




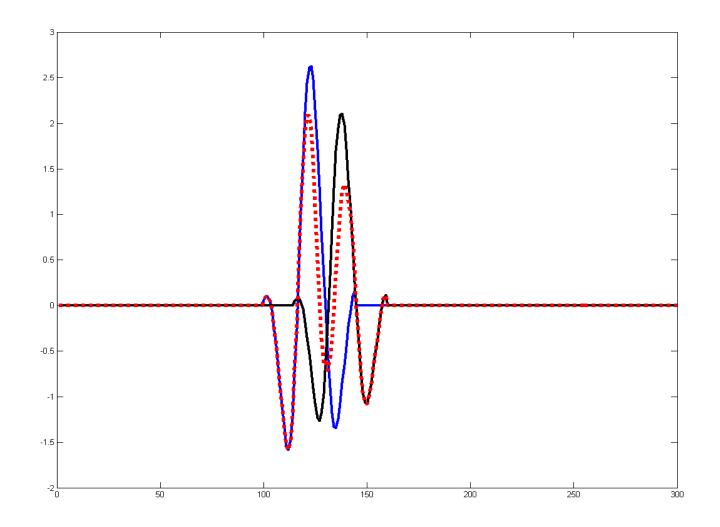




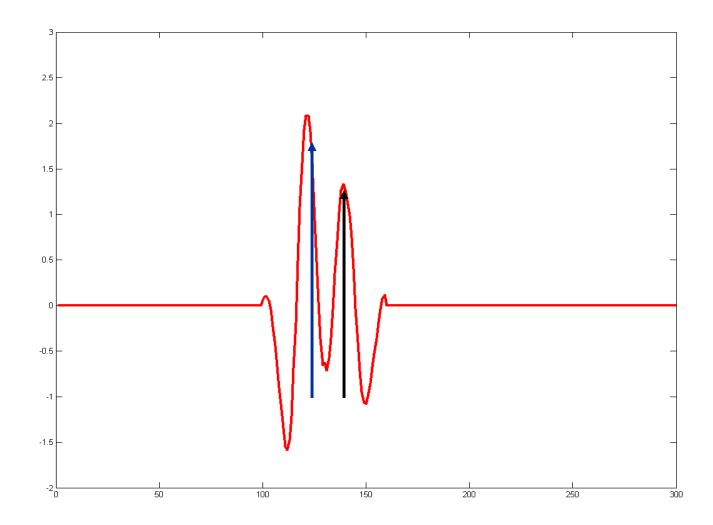
Overlapping Peaks Occur when Reflections are Close Together



Reflections Add Up



Overlapping Peaks Must be Filtered to Find Impulse Response

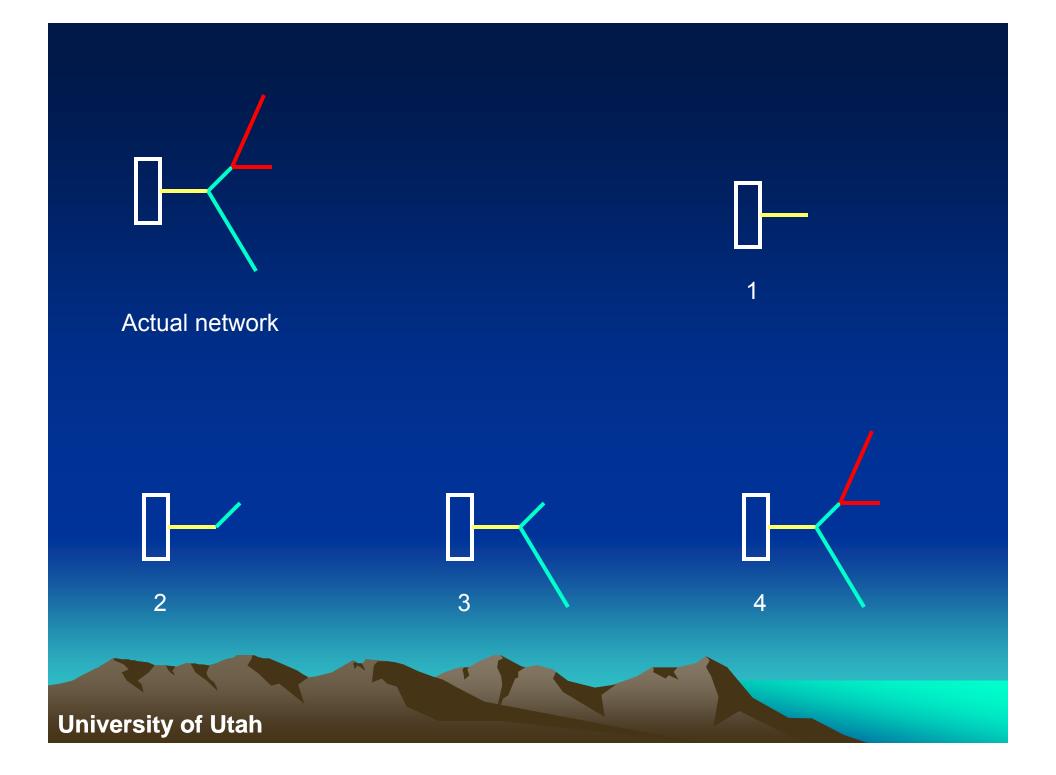


Flow chart of branch network detection

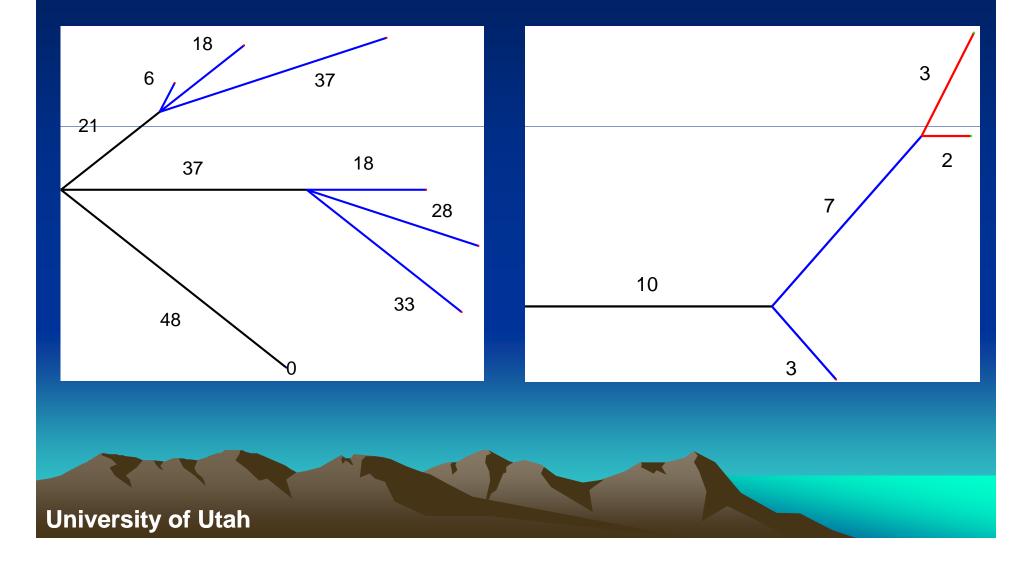
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Mapping Algorithm

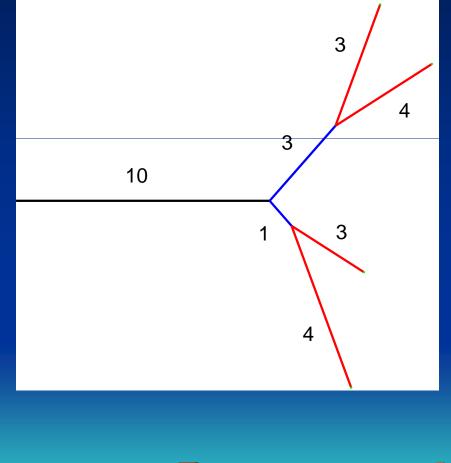


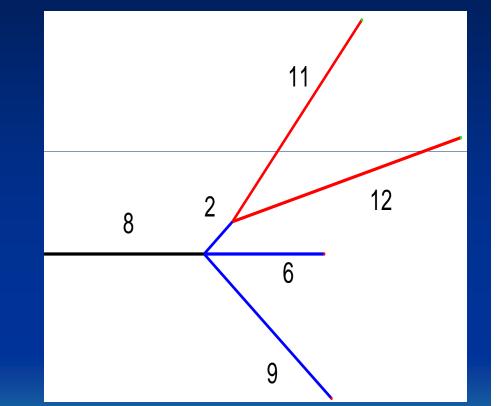


(simulated Network)



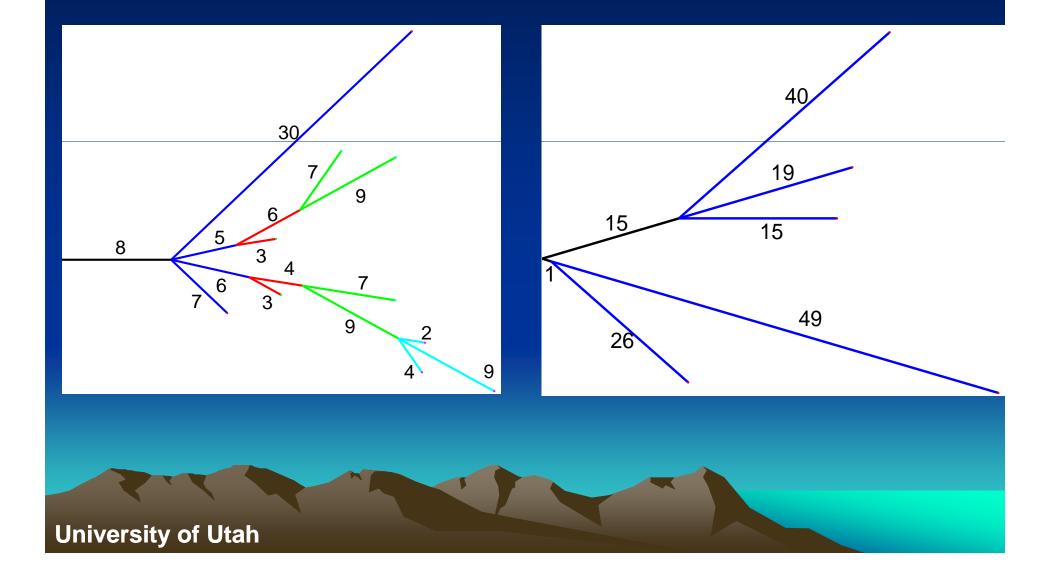
(simulated Network)



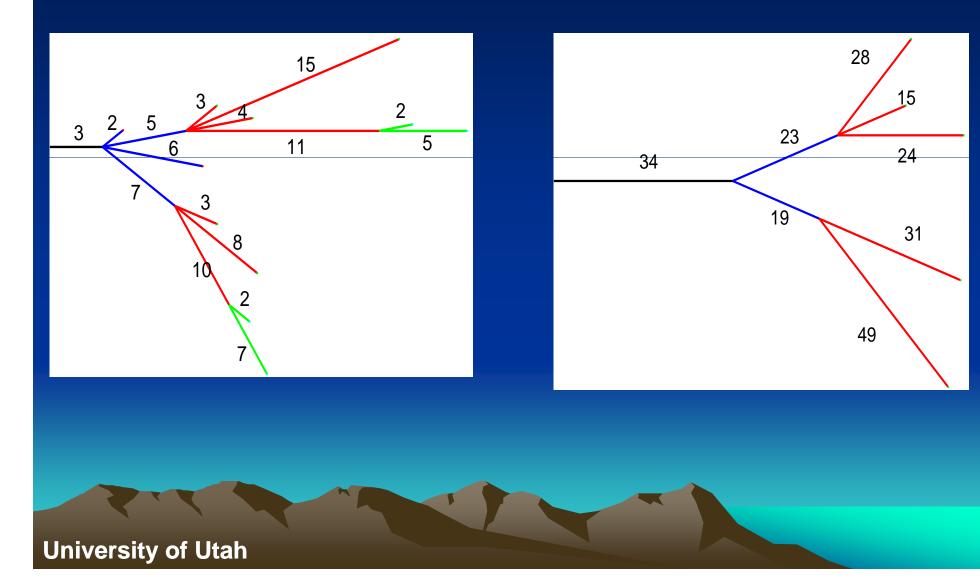




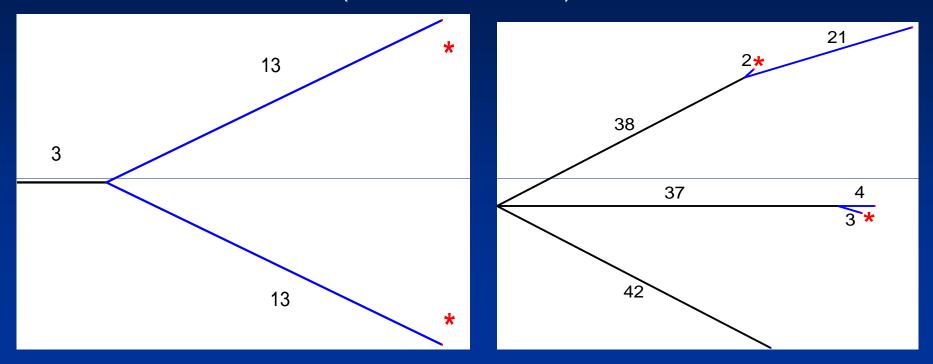
(simulated Network)



(simulated Network)

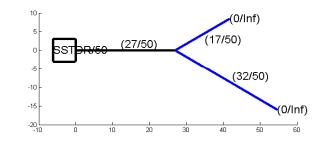


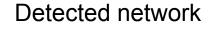
(simulated network)

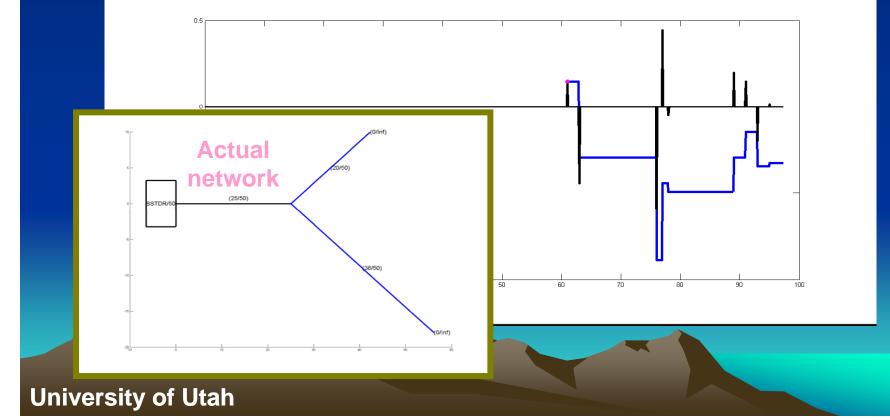


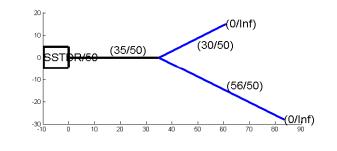
Reason: Ambiguity at 16'

Reason: Ambiguity at 40'

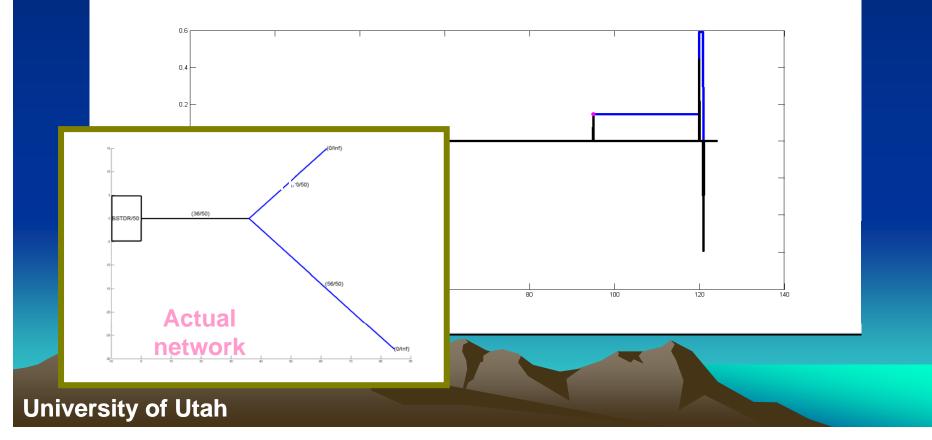


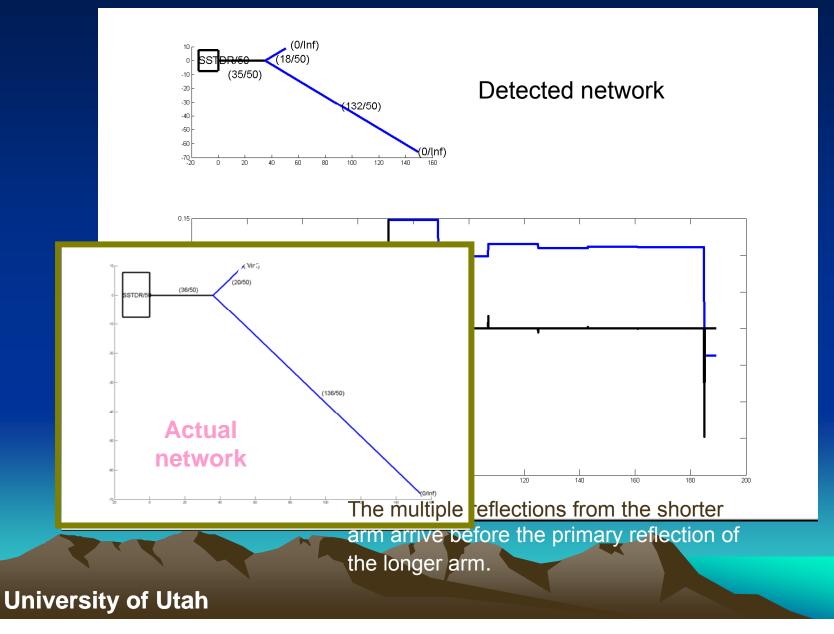


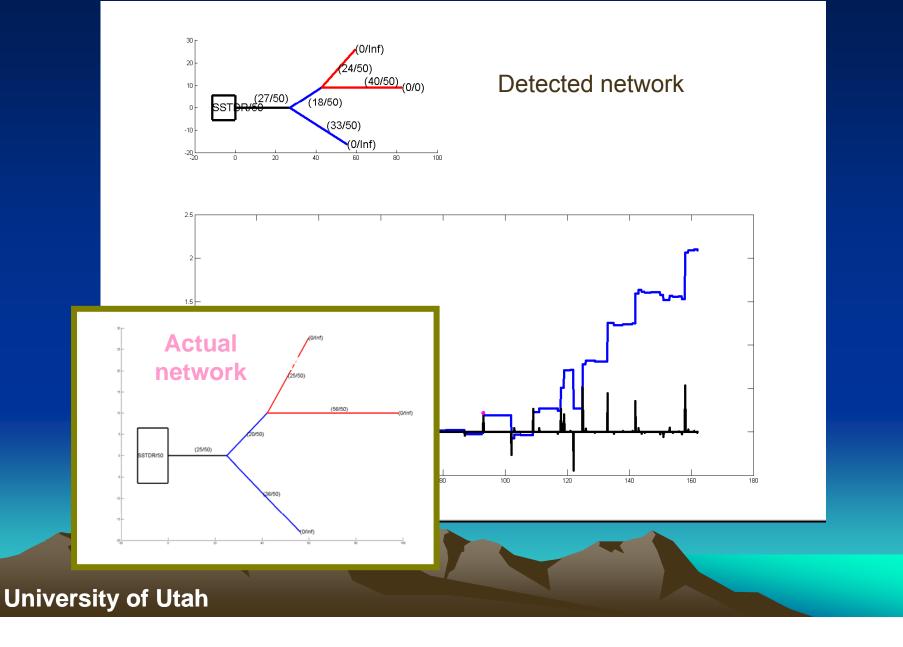


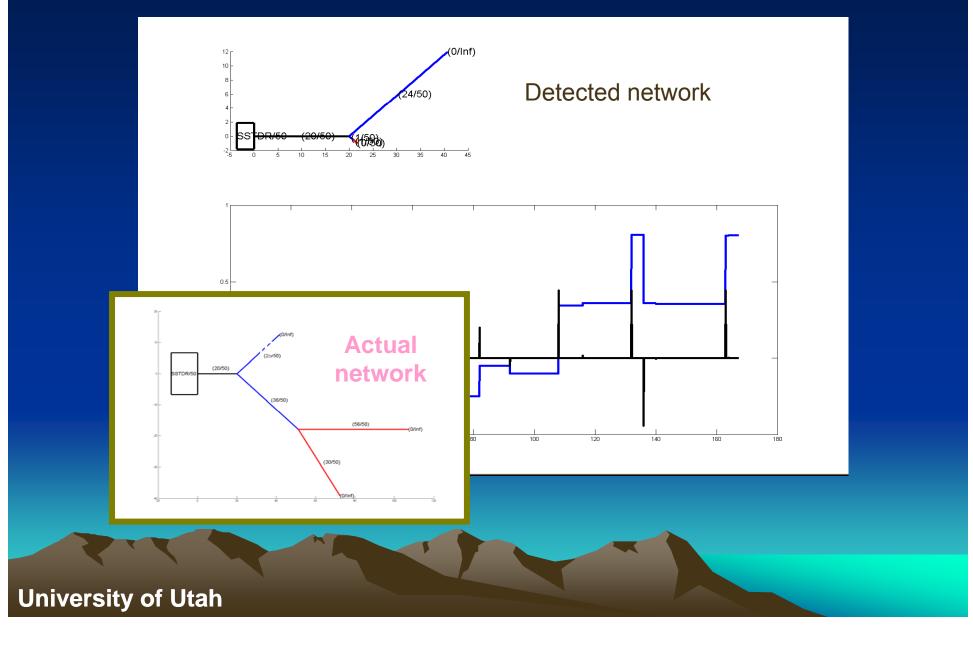


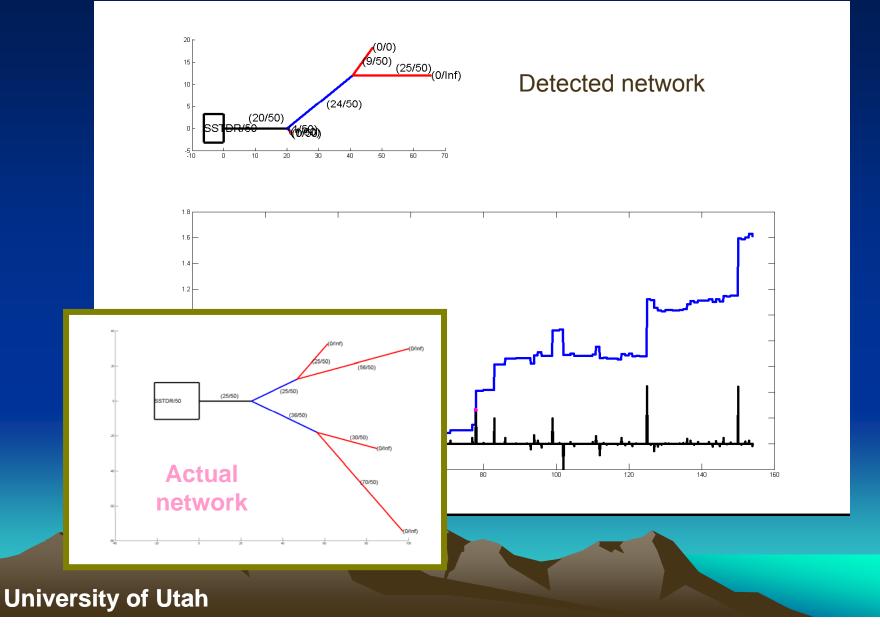
Detected network



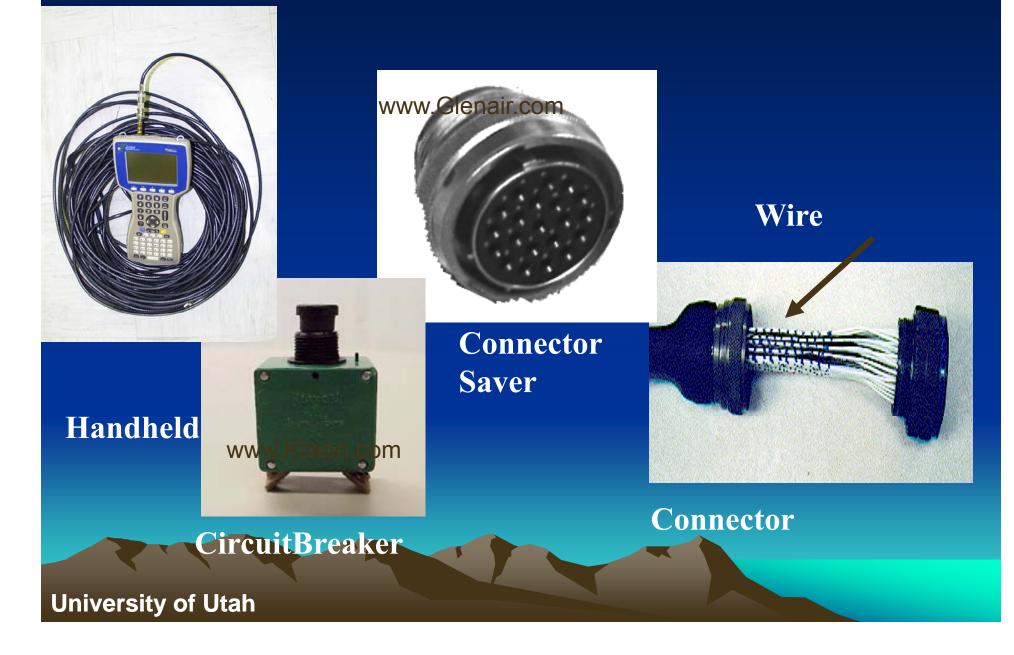








Potential Sensor Locations



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Questions ?

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University of Utah

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